

A proposal of “2R-R + segment DAC” architecture and its design methodology

○菅原 光俊 *1*2, 盛 健次 *1*2, 宮原 正也 *1, 松澤 昭 *1

Mitsutoshi Sugawara *1*2, Kenji Mori *1*2, Masaya Miyahara *1, Akira Matsuzawa *1

*1 Tokyo Institute of Technology 東京工業大学, *2 JST, CREST 独立行政法人科学技術振興機構

sugawara@ssc.pe.titech.ac.jp

Abstract: It is well known that b bit R-DAC consisting of R-2R type for upper b-n bits and 2R segments for lower bits.

Targeting design automation, we propose a general calculation methodology for the DACs including n=0 and n=b. A required accuracy of unit resistor is calculated as $m \cdot 2^{-b+n}$, where m is margin. Its standard deviation σ is given as $\text{Pelgrom_coef}/\sqrt{L \cdot W}$. As well known, W/L comes from given resistor value. L, W can be easily calculated from the equations.

The equation above mentions that same area value L*W for either R or 2R, due not to depend on area. Hence we propose “2R-R+segment DAC” shown in above figure, consisting of 2R as unit resistor and R as a parallel of two 2Rs. Because of bigger number of 2R than R in the figure, it is realized in almost half size of previous “R-2R+segment DAC”.

